

Hitachi has a complete solution to your routine analysis work



Scanning Electron Microscopes
SU3800



Ion Milling System
ArBlade 5000



Ultra-high Resolution
Scanning Electron Microscope
Regulus Series

Observing, measuring and analyzing technologies contribute to new innovations in various industrial fields.



Field Emission Scanning
Transmission Electron Microscope
HD-2700



Focused Ion and Electron Beam System
Ethos NX5000



Field Emission
Transmission Electron Microscope
HF5000